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## APPLICANTS

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## \*\* CONTINUING DATA \*\*\*\*\*

This application is a DIV of 09/434,490 11/05/1999 PAT 6,407,563

*Verified for H*

## \*\* FOREIGN APPLICATIONS \*\*\*\*\*

JAPAN JP11-66621 03/12/1999

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## IF REQUIRED, FOREIGN FILING LICENSE GRANTED

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Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY JAPAN	SHEETS DRAWING 33	TOTAL CLAIMS 2114	INDEPENDENT CLAIMS 72
35 USC 119 (a-d) conditions met <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance				
Verified and Acknowledged <i>John A. Hoyer</i> Examiner's Signature Initials				

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## TITLE

Semiconductor device test method

FILING FEE	FEES: Authority has been given in Paper	<input type="checkbox"/> All Fees
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